AC FE-LEEM P90 Double Stage Results

Application Note

This application note shows results obtained with the SPECS FE-LEEM P90, measured at the Kamerlingh Onnes Laboratory at the University of Leiden in April 2011. The sample is graphene on SiC. Several layer thicknesses are visible, with the number of graphene layers between one and four layers. The images are taken in bright field mode.
The ultimate resolution visible in the images is 1.4 nm, taken across an atomic step, with a 20% - 80% intensity criterion.

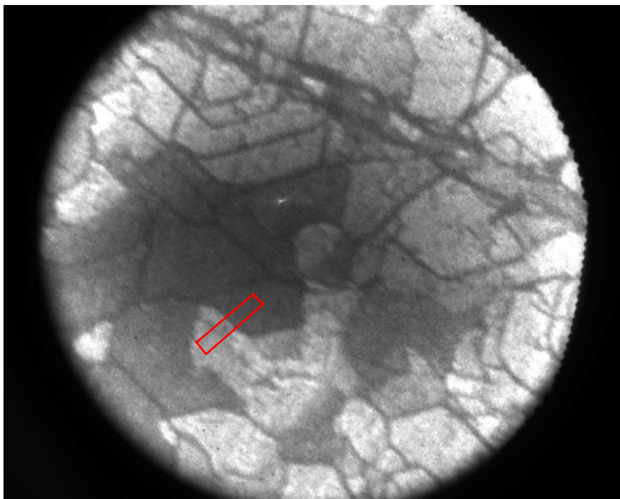

Fig. 1: Graphene on SiC, field of view 660 nm

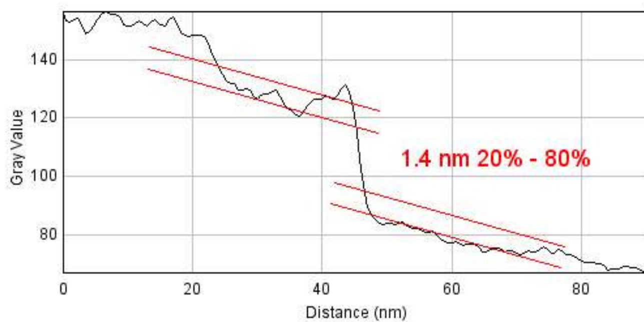

Fig. 2: Line scan of fig. 1. The scan has been averaged over a 30 pixel wide line.

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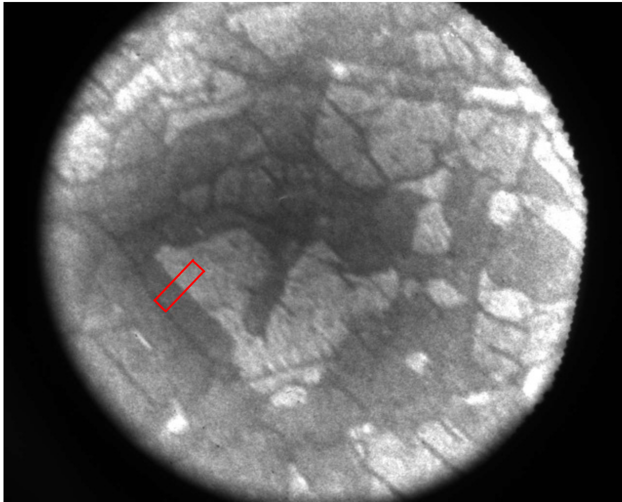

Fig. 3: Graphene on SiC, field of view 660 nm

Fig. 4: Line scan of fig. 3. The scan has been averaged over a 30 pixel wide line.

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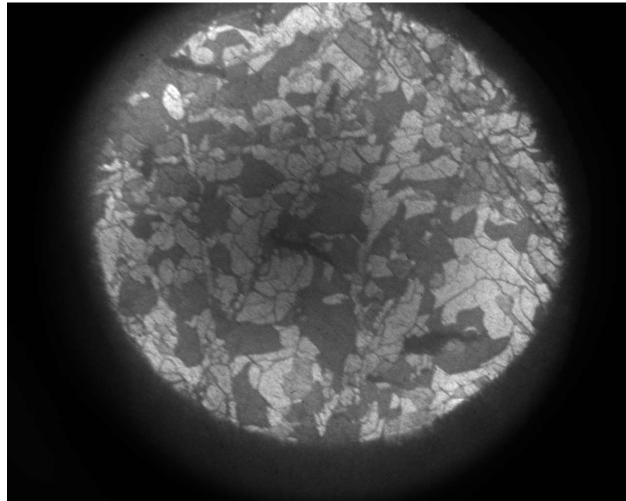

Fig. 5: Graphene on SiC, field of view 2300 nm

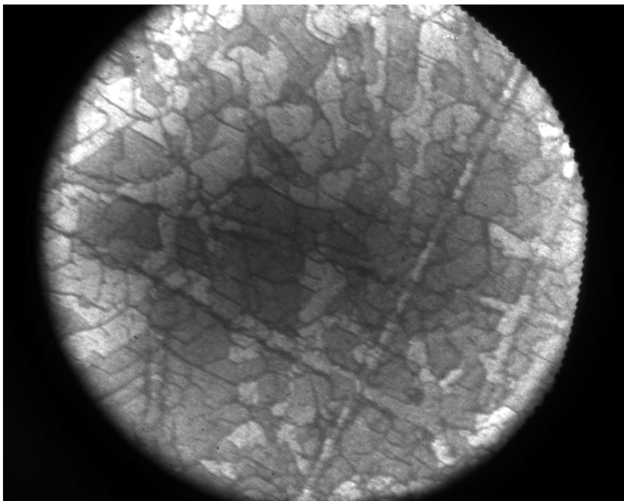

Fig. 6: Graphene on SiC, field of view 1300 nm

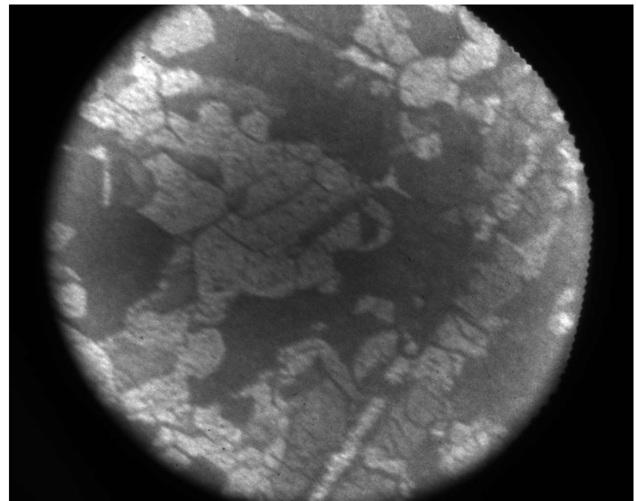

Fig. 7: Graphene on SiC, field of view 1000 nm

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